Appendix A. Supplementary Data

Thermochemistry of Nitrogen-Doped Reduced Graphene Oxides

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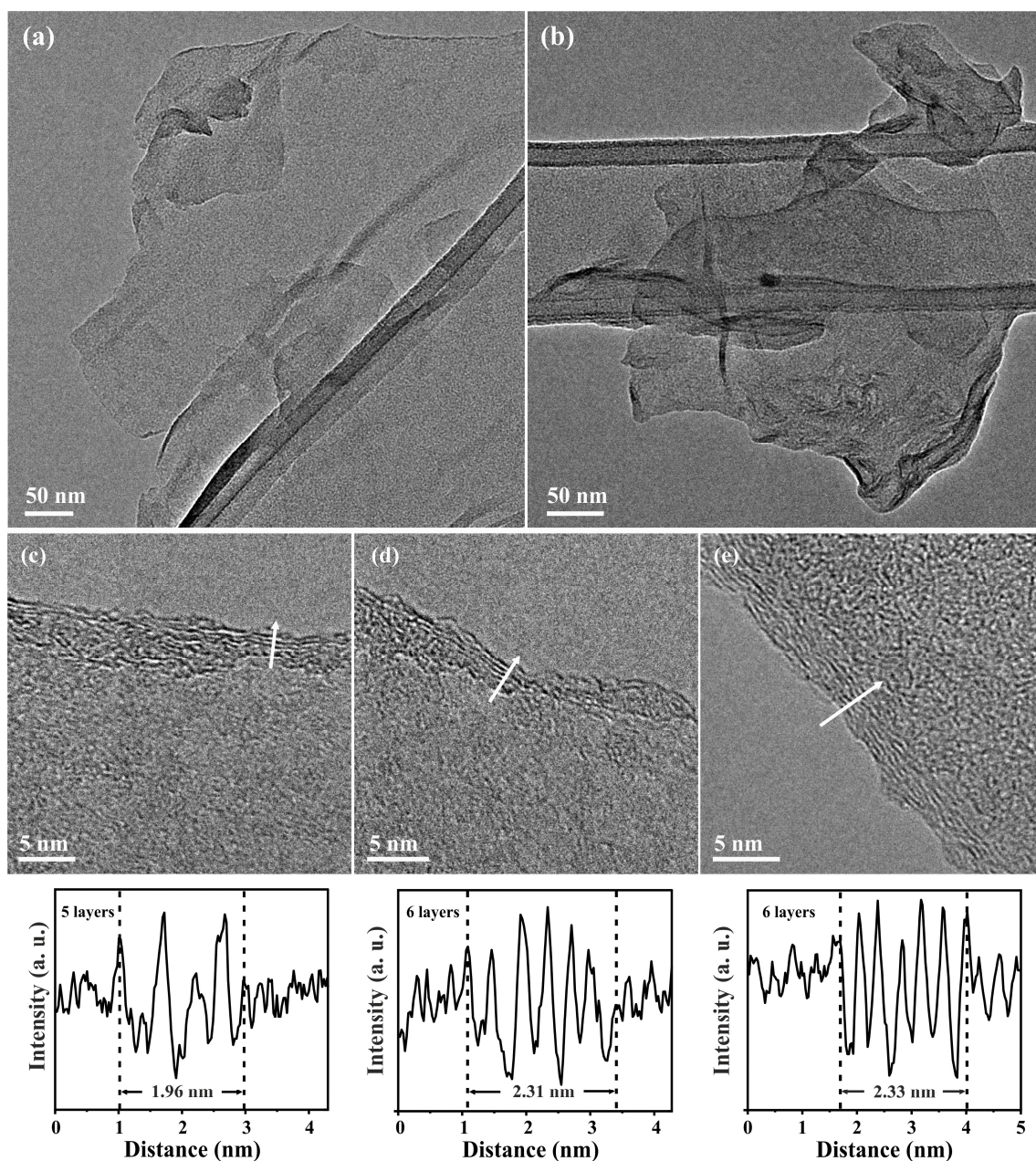
08193 Bellaterra, Spain

Figure S1. TEM images of N-doped rGO prepared by ammonolysis treatment of GO at **(a)** 600 °C and **(b)** 500 °C. (c-e) HRTEM images of N-doped rGO (600 °C, NH_3) with their corresponding intensity profile confirming the presence of five and six layered specimens (few layers N-doped rGO).
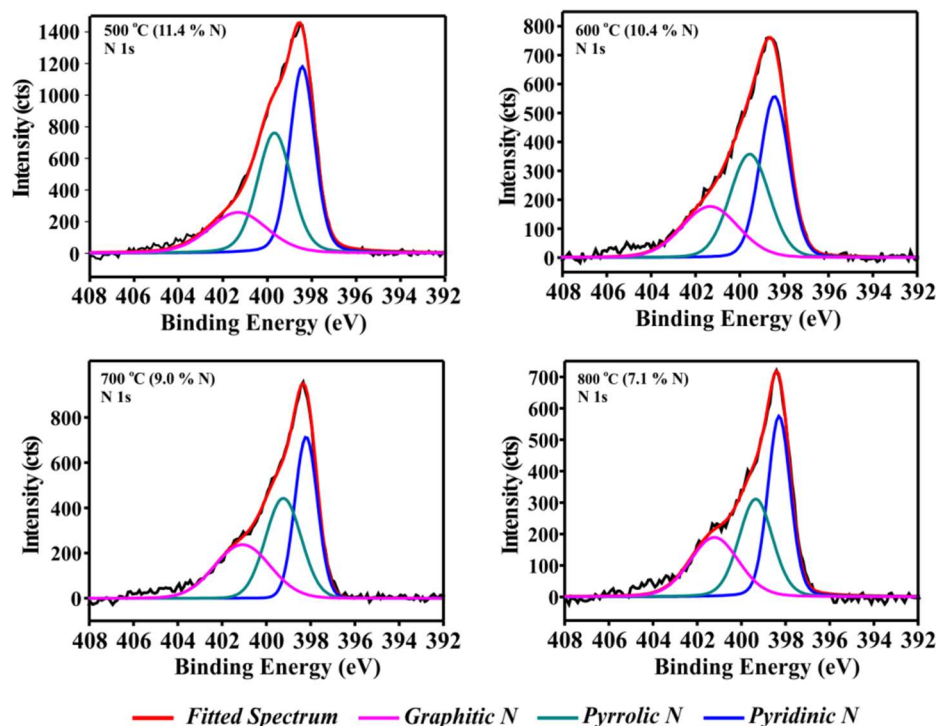
Figure S2. Fitted XPS data over the N 1s region of nitrogen-doped reduced graphene oxide samples.
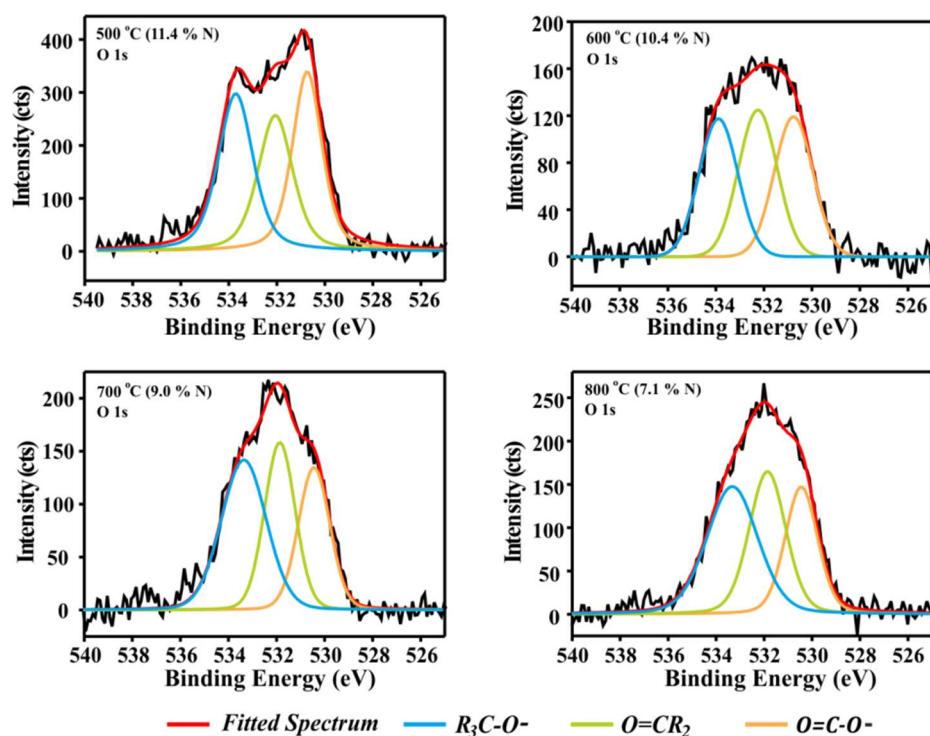

Figure S3. Fitted XPS data over the O 1s region of nitrogen-doped reduced graphene oxide samples.

Table S1. Composition of N-doped rGO samples as determined by EA (wt. %).

Sample	Elemental composition (wt. %)		
	N	C	H
1 (800 ºC)	8.5	80.0	0.6
2 (700 ºC)	10.7	81.8	0.5
3 (600 ºC)	12	80.9	0.6
4 (500 ºC)	13	78.5	0.9